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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/813,758	03/31/2004	Samit Kumar Basu	140361-1/YOD GERD:0123	5263	
6147 7590 03/19/2010 GENERAL ELECTRIC COMPANY			EXAMINER		
GLOBAL RESI	J C	BITAR, NANCY			
ONE RESEARCH CIRCLE PATENT DOCKET RM. BLDG. K1-4A59		4A59	ART UNIT	PAPER NUMBER	
NISKAYUNA,	NISKAYUNA, NY 12309			2624	
			NOTIFICATION DATE	DELIVERY MODE	
			03/19/2010	ELECTRONIC	

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Notice of the Office communication was sent electronically on above-indicated "Notification Date" to the following e-mail address(es):

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	Application No.	Applicant(s)			
	10/813,758	BASU ET AL.			
Office Action Summary	Examiner	Art Unit			
	NANCY BITAR	2624			
The MAILING DATE of this communication ap Period for Reply	opears on the cover sheet with the c	correspondence address			
A SHORTENED STATUTORY PERIOD FOR REPLAY WHICHEVER IS LONGER, FROM THE MAILING IDENTIFY OF THE MAILING	DATE OF THIS COMMUNICATION .136(a). In no event, however, may a reply be tird d will apply and will expire SIX (6) MONTHS from tte, cause the application to become ABANDONE	N. nely filed the mailing date of this communication. D (35 U.S.C. § 133).			
Status					
1) ☐ Responsive to communication(s) filed on 14 a 2a) ☐ This action is FINAL . 2b) ☐ Th 3) ☐ Since this application is in condition for allowed closed in accordance with the practice under	is action is non-final. ance except for formal matters, pro				
Disposition of Claims					
4) Claim(s) 12-17 is/are pending in the application 4a) Of the above claim(s) is/are withdress. 5) Claim(s) is/are allowed. 6) Claim(s) 12-17 is/are rejected. 7) Claim(s) is/are objected to. 8) Claim(s) are subject to restriction and/	awn from consideration.				
 9) The specification is objected to by the Examir 10) The drawing(s) filed on 31 March 2004 is/are: Applicant may not request that any objection to the Replacement drawing sheet(s) including the corre 11) The oath or declaration is objected to by the Examination 	a)⊠ accepted or b)⊡ objected to e drawing(s) be held in abeyance. Sec ction is required if the drawing(s) is ob	e 37 CFR 1.85(a). jected to. See 37 CFR 1.121(d).			
Priority under 35 U.S.C. § 119					
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No. 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 					
Attachment(s) 1) Notice of References Cited (PTO-892)	4) 🔲 Interview Summary				
2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date 5) Notice of Informal Patent Application Other:					

Application/Control Number: 10/813,758 Page 2

Art Unit: 2624

DETAILED ACTION

Response to Arguments

- 1. Applicant's response to the last Office Action, filed 7/24/2009, has been entered and made of record.
- 2. Claims 12-30 are currently pending.
- 3. Applicants arguments filed 11/25/2009 have been fully considered and are persuasive but are most in view of the new ground(s) of rejection.
- 4. Applicant Affidavit of Bruno DeMan under 37 C.F.R 1.132 has been accepted by the examiner

Claim Rejections - 35 USC § 103

- 5. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 6. Claims 12-30 are rejected under 35 U.S.C. 103(a) as being unpatentable over Shih et al (US 2005/0152504) in view of Liang et al (US 7,187,794)

As to claim 12, Shih teaches a method for generating a variance map from measured projection data acquired from a tomography system comprising:

accessing the measured projection data from the tomography system (A tomography system 100 comprises an imaging system 102; note that figure 3 teaches acquire an object projection of an object; 310); formulating a variance measure based upon the measured projection data

Art Unit: 2624

(generating the variance reconstruction from the variance projections, paragraph [0010]); and generating a variance map from the variance measure using a reconstruction algorithm (the variance projection includes an intensity map and positional data for the perspective that is common to the standard and object projections; note that 3D variance reconstruction of the variations between the object and the standard is generated, and the object is qualified based on the variance reconstruction, Paragraph [0043]) While Shih meets a number of the limitations of the claimed invention, as pointed out more fully above, Shih fails to specifically teach the variance map has been generated from variance measure. Specifically, Liang et al teaches treating noise in low-dose CT projections and reconstructed images. The method comprises generating a curve for variance and means given a set of raw data, fitting the curve by a functional form, and determining, for a fitted curve, a transformed space having substantially constant variance for all means. The method further comprises applying a domain specific filter in a sinogram domain of the set of raw data, and applying an EPS filter in an image domain of the set of raw data after filtering in the sinogram domain (see abstract figure 5 and figure 9). it would have been obvious to one of ordinary skill in the art to generate the variance map from the projection data as taught by Man et al since one would have been motivated to make such modification to reduce artifact thus improving image quality. Therefore, the claimed invention would have been obvious to one of ordinary skill in the art at the time of the invention by applicant.

As to claim 13, Shih teaches determining variability of a mean pixel value caused by noise factors and artifact factors associated with the measured projection data based upon the variance measure (any pixel in the variance projection intensity map that exceeds a particular

threshold value can be a variant portion. Alternatively, a variant portion can be defined as any portion of the intensity map in which a threshold number of pixels within a given area each exceed threshold intensity. Threshold values, for example, can be fixed values or can be set by a user to vary the sensitivity. It will be appreciated that more complex algorithms can also be applied to identify variant portions, paragraph [0037]; figure 4; see also Liang figure 2 and column 12 lines 58- column 13 lines 1-66).

As to claim 14, Shih teaches the method of claim 12, wherein formulating a variance measure is based on a statistical model (figure 4, 450,460,470; it is known to one skilled in the art that the numerical analyzer can include statistical model; see Liang figure 2 and column 3 lines 1-65).

As to claim 15, Liang et al teaches the method of claim 12, wherein the reconstruction algorithm is a weighted filtered back projection reconstruction algorithm or a fast reconstruction algorithm such as a Fourier-based algorithm, a hierarchical algorithm, or a coarse reconstruction based on down sampled projection data and/or image data (column 5 line 57-column 6 lines 1-17)

As to claim 17, Shih et al teaches the method of claim 15, wherein the reconstruction algorithm is adapted to operate on the variance measure to generate the variance map (It will be appreciated that more complex algorithms can also be applied to identify variant portions, paragraph [0037])

As to claim 18, Shih teaches the method of claim 12 further comprises displaying, analyzing or processing the variance map (figure 4, numerical analyzer; see Liang et al (figure 8A-8C).

As to claim 19, Shih teaches the method of claim 12, wherein the measured projection data is reconstructed to generate original image data and wherein the original image data is displayed or analyzed based upon or in conjunction with the variance map (a graphical user interface can provide variance data to the operator. For example, a graphics generator of the numerical analyzer 470 can superimpose the variance reconstruction of the variations over a stored 3D reconstruction of the standard to provide the operator with a visual indication of the differences between the object and the standard, paragraph [0045]).

As to claim 20, Shih teaches the method of claim 12, further comprising identifying features of interest in the original image data based upon the variance map (identify variant portions of the variance projection, 340; figure 3).

The limitation of claims 21-24 has been addressed in claims 12-15

The limitation of claim 25 has been addressed in claim 17.

As to claim 26, Shih et al teaches the method of claim 21, wherein the measured projection data is reconstructed to generate original image data and wherein the original image data is displayed analyzed or processed based upon the variance map (a graphical user interface can provide variance data to the operator. For example, a graphics generator of the numerical analyzer 470 can superimpose the variance reconstruction of the variations over a stored 3D reconstruction of the standard to provide the operator with a visual indication of the differences

between the object and the standard. The composite of the standard and variance reconstructions can be enhanced, for example through the use of colors or shading, to highlight defects for the operator. It will be appreciated that such graphics can also be displayed while object qualification is being determined automatically by the numerical analyzer 470, paragraph [0045]; figure 5; see also Man et al figure 1 and 6).

The limitation of claim 27 has been addressed in claim 20.

The limitation of claim 28 has been addressed above on that claim 18 is a system claim whereas claim 1 is a method claim .Therefore; claim 28 is analyzed as previously discussed.

The limitation of claims 29 and 30 has been addressed above

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to NANCY BITAR whose telephone number is (571)270-1041. The examiner can normally be reached on Mon-Fri (7:30a.m. to 5:00pm).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Vikkram Bali can be reached on 571-272-7415. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/813,758 Page 7

Art Unit: 2624

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/Nancy Bitar/ Examiner, Art Unit 2624

/Wes Tucker/ Primary Examiner, Art Unit 2624